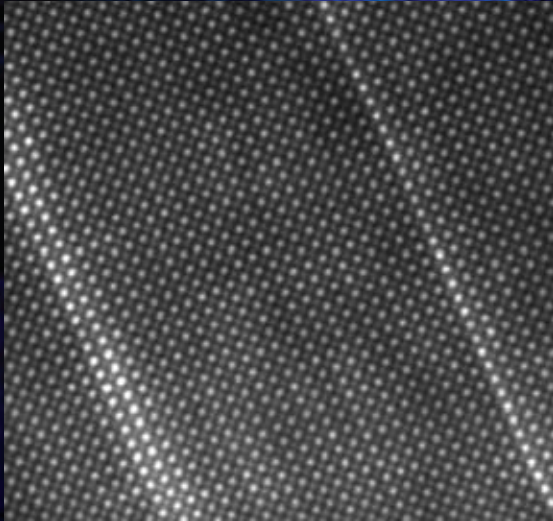
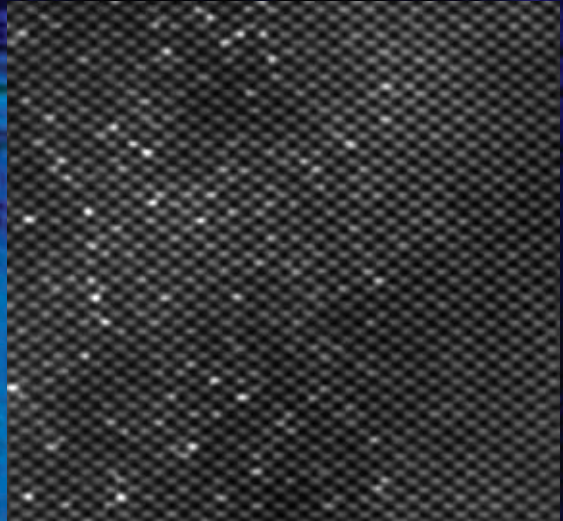


# JEOL Ultra-high point-to-point resolution TEM



HAADF STEM showing bright La columns



Individual Sb atoms in Si matrix

Photos courtesy of David Muller,  
Lucent Technologies

*Extreme Imaging*



Model JEM-2100F

**scan**

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